



J O U R N A M E N T

ACADEMIC JOURNAL INDEXING & IMPACT ANALYSIS



Certificate of Indexing

This is to certify that the academic journal

**ieee international symposium on semiconductor
manufacturing conference proceedings**

has been formally reviewed and admitted to the Journalment Index of Academic Journals, having satisfied the standards required for scholarly indexing, and is hereby awarded a verified Journalment Impact Score@endif.

@if(\$isScored)



Journament Editorial Board

AUTHORIZED SIGNATORY

REGISTRY № JML-16721

Verify at journalment.com/verify/16721

22 November 2019

DATE OF INDEXING